

<b>Search Notes</b> 	<b>Application/Control No.</b>  <b>10/644,377</b>	<b>Applicant(s)/Patent under Reexamination</b>  <b>WIELAND ET AL.</b>
	<b>Examiner</b>  <b>Wayne Langel</b>	<b>Art Unit</b>  <b>1754</b>

SEARCHED				
Class	Subclass	Date	Examiner	
502	339	9-1-05	WAL	
423	652	9-1-05	WAL	
<u>above to</u>				
		date	4-19-06	WAL
<u>above to</u>		8-1-06	WAL	
		date		
423	651	8-2-06	WAL	
422	211	8-2-06	WAL	
422	222	8-2-06	WAL	
502	73	8-2-06	WAL	
502	74	8-2-06	WAL	
502	267	8-2-06	WAL	
502	242	8-2-06	WAL	
502	243	8-2-06	WAL	
502	249	8-2-06	WAL	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
423	652	8-2-06	WAL
422	222	8-2-06	WAL
502	325	8-2-06	WAL
502	339	8-2-06	WAL
502	330	8-2-06	WAL

**Search Notes (continued)**

Application/Control No.

10/644,377

Examiner

Wayne Langel

Applicant(s)/Patent under  
Reexamination

WIELAND ET AL.

Art Unit

1754

**SEARCHED**

Class	Subclass	Date	Examiner
502	250	8-2-06	WAL
502	261	8-2-06	WAL
502	262	8-2-06	WAL
502	302	8-2-06	WAL
502	325	8-2-06	WAL
502	328	8-2-06	WAL
502	330	8-2-06	WAL
502	332	8-2-06	WAL
502	334	8-2-06	WAL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner